

What is Claimed Is:

1. A method in an integrated test device, the method comprising:
performing, using network logic on the integrated test device, first network device operations on received data and outputting network data according to a media independent interface (MII) based protocol;
- 5 performing prescribed test operations on the network data using first test logic on the integrated test device and outputting test data based on the MII-based protocol; and
converting the test data into analog-based signals for transmission on a prescribed network medium using second test logic on the integrated test device.
2. The method of claim 1, wherein the step of performing first network device operations includes switching the received data according to prescribed switching logic.
3. The method of claim 2, wherein the step of performing prescribed test operations includes second converting the network data, having a first data rate, into the test data having a second data rate substantially greater than the first data rate.
4. The method of claim 3, wherein the first data rate is about 250 kbps and the second data rate is about 10Mbps.
5. The method of claim 1, wherein the converting step includes converting the test data into 10 Base-T compliant analog signals.
6. The method of claim 1, wherein the converting step includes converting the test data into 100 Base compliant analog signals.
7. An integrated network test device comprising:
network logic configured for performing prescribed network device operations and outputting network data based on a media independent interface (MII) based protocol;
first test logic configured for performing prescribed test operations on the network data and
5 outputting test data based on the MII-based protocol; and

second test logic configured for converting the test data, output from the first test logic according to the MII-based protocol, into analog-based signals for transmission on a prescribed network medium.

8. The device of claim 7, wherein the second test logic is configured for converting the test data into 10 Base-T compliant analog-based signals.

9. The device of claim 7, wherein the second test logic is configured for converting the test data into 100 Base compliant analog-based signals.

10. The device of claim 7, wherein , wherein the first test logic is configured for converting the network data, having a first data rate of about 250 kbps, to the test data having a second data rate of about 10Mbps.